

Google patents

fault transient power abnormality test pattern

Search Pat

Filing date

☐ Return patents filed anytime

☒ Return patents filed between and

Patents

Patents **1 - 1** on **fault transient power abnormality test pattern**. (0.04 seconds)

› **List view**

[Cover view](#)

[System to assess the starting performance of a turbine](#)

US Pat. 5748500 - Filed Nov 14, 1995 - Electric Power Research Institute, Inc.

The risk matrix output for each specific shutdown **fault** points to those risks ... Speed **transient** at light-off 5. Speed reference versus measured speed 6. ...

› **Sort by relevance**

[Sort by date \(new first\)](#)

[Sort by date \(old first\)](#)

Stay up to date on these results using the patents RSS feed on **fault transient power abnormality test pattern**.

› **Any status**

[Issued patents](#)

[Applications](#)

fault transient power abnormality test pattern

Search Patents

[Advanced Patent Search](#)

[Google Home](#) - [About Google](#) - [About Google Patents](#) - [Google Patents Help](#)

©2009 Google

Google patents

test pattern transient power supply current abr

Search Pat

Filing date

☐ Return patents filed anytime

☒ Return patents filed between Jan ▾ 1970 and Apr

Patents

Patents 1 - 7 on **test transient power supply current abnormality OR anomaly.** (0.10 seconds)

› List view

[Cover view](#)

› Sort by relevance

[Sort by date \(new first\)](#)

[Sort by date \(old first\)](#)

› Any status

[Issued patents](#)

[Applications](#)

[Dynamic burn-in test equipment](#)

US Pat. 6215324 - Filed Jan 5, 2000 - Nippon Scientific Co., Ltd.

And the difference causes **current** flows in the **test** pattern generator ...

Therefore, when the currents flowing in the higher level **power supply** lines and

...

[Transient test of suspension electronics for gyroscope](#)

US Pat. 4654582 - Filed Jul 8, 1985 - The United States of America as represented by the Secretary of the Air Force

10 shows the sensor 1042 of the high voltage **power supply** 16. ... functional

electronic subdivisions of the suspension system for signal **abnormality**, ...

[Load protection circuit](#)

US Pat. 5055703 - Filed Feb 13, 1990 - Perma Power Electronics, Inc.

15 16 **power supply** 2, which in turn constantly powers an inverter 3. ... In the

event of **power** line **abnormality**, the phase detector and control circuit CC ...

[Standby power supply](#)

US Pat. 4956563 - Filed Nov 9, 1987 - Perma Power Electronics, Inc.

In the event of **power** line **abnormality**, the phase acting circuit breaker which

does not **supply** an alterna- detector and control circuit CC acts on the ...

[Modular power quality monitoring device](#)

US Pat. 6404348 - Filed Mar 23, 1999 - Power Quality Consultants, Inc.

The detectable electrical phenomenon includes SPD/ PQE status, voltage levels,

current draw, **power** surges, phase outages, phase shifting, **power** factor, ...

[Semiconductor integrated circuit having therein circuit for detecting ...](#)

US Pat. 5343479 - Filed Oct 31, 1990 - NEC Corporation

In this spec- level signal **abnormality** detection circuits, ... creased impedance

of a voltage **supply** line of a **test** 50 *he/lrst Concentrating circuit so ...

[Steering stabilizing method and apparatus for suppressing the weave mode](#)

US Pat. 4951199 - Filed Nov 16, 1987

test transient power supply current abnormali

Search Patents

Advanced Patent Search

[Google Home](#) - [About Google](#) - [About Google Patents](#) - [Google Patents Help](#)

©2009 Google

Google

patents

Filing date ☐ Return patents filed anytime

☒ Return patents filed between 1970 and

Patents

Patents **1 - 20** on **test pattern transient power supply current**. (0.06 seconds)

▸ **List view**

[Cover view](#)

▸ **Sort by relevance**

[Sort by date \(new first\)](#)

[Sort by date \(old first\)](#)

▸ **Any status**

[Issued patents](#)

[Applications](#)

Integrated circuit **test power supply**

US Pat. 5773990 - Filed Sep 29, 1995 - Megatest Corporation

Testing a CMOS device quiescent **power supply current** (IDDQ) is a useful ...

transient accumulated charge, and the device under **test power supply** 102 is set

...

Quiescent **power supply current test** method and apparatus for integrated ...

US Pat. 5731700 - Filed Jun 19, 1996 - LSI Logic Corporation

For example, a particular More specifically, the quiescent **power supply current**

test pattern can be stored in a memory device, and then read IDDQ is sensed ...

Integrated circuit fault testing system based on **power** spectrum analysis of ...

US Pat. 5949798 - Filed Feb 4, 1997 - NEC Corporation

20 ing a **test pattern** to the CMOS integrated circuit under **test**: FIG. shows ...

4' under **test** deriving a **power** spectrum of the **supply current** detected by to ...

Semiconductor integrated circuit fault analyzing apparatus and method therefor

US Pat. 5521516 - Filed Dec 6, 1994 - NEC Corporation

Upon completion of setting the conditions, the ON/OFF control means 3a turns on

the **power supply** for the DUT 8 (step S204), and a designated **test pattern** is ...

Method for fabricating integrated circuit (IC) dies with multi-layered ...

US Pat. 6423558 - Filed Feb 25, 2000 - Advantest Corporation

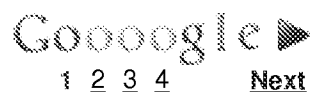
The quiescent **power supply current test** is a procedure which assumes a ... 1997;

and for **transient power supply current test**, a description is given, ...

Apparatus for reducing **power supply** noise in an integrated circuit

US Pat. 6339338 - Filed Jan 18, 2000 - Formfactor, Inc.

Power control 1C 52 includes a **pattern** generator 54 that carries out the **pattern**



test pattern transient power supply current

Search Patents

Advanced Patent Search

[Google Home](#) - [About Google](#) - [About Google Patents](#) - [Google Patents Help](#)

©2009 Google

Google

test pattern transient power supply current and

Search Pat

Filing date

☐ Return patents filed anytime

☒ Return patents filed between 1970 and

Patents

Patents 1 - 11 on test pattern transient power supply current analysis points. (0.05 seconds)

› List view

[Cover view](#)

› Sort by relevance

[Sort by date \(new first\)](#)

[Sort by date \(old first\)](#)

› Any status

[Issued patents](#)

[Applications](#)

[Integrated circuit fault testing system based on power spectrum analysis of ...](#)

US Pat. 5949798 - Filed Feb 4, 1997 - NEC Corporation

20 ing a **test pattern** to the CMOS integrated circuit under **test**: FIG. shows ...

4' under **test** deriving a **power** spectrum of the **supply current** detected by to ...

[Method and apparatus for testing semiconductor integrated circuits](#)

US Pat. 5760599 - Filed Aug 6, 1996 - Sharp Kabushiki Kaisha

In the CMOS, since a **transient current** with larger difference at both ends.

...

changes of the **power** source **current** due to the **test pattern**. a^so detected, ...

[Method for the continuous flow make of customized planar electrical circuits](#)

US Pat. 4935093 - Filed Feb 11, 1988

Via line 704, the result of the **current** state of etching measurement is ... duty

cycle of a suitable polarizing **power supply** for providing said **current**. ...

[Automated computerized magnetic resonance detector and analyzer](#)

US Pat. 5592086 - Filed Oct 19, 1994

a tuned curcuit and a series of chokes to isolate the **power supply** from the output circuit. ... The output of the modulator 16 is a **test pattern** signal 21, ...

[Computer and electromagnetic energy based mass production method for the ...](#)

US Pat. 5294290 - Filed Sep 30, 1992

Via line 704, the result of the **current** state of '0 forms well for obtaining a fast ... polarizing **power supply** for providing said speed process conditions.

...

[A DC power supply controller](#)

US Pat. 5656923 - Filed Apr 10, 1995 - The Whitaker Corporation

(9) switching **pattern** of the transistor 162, but the **current** loop of the ...

with a load more complex than microcontroller **power** and time. a resistor. ...

test pattern transient power supply current an

Search Patents

Advanced Patent Search

[Google Home](#) - [About Google](#) - [About Google Patents](#) - [Google Patents Help](#)

©2009 Google

Google

patents **fault location testing transient power supply cu**

Search Patents

Filing date
☐ Return patents filed anytime
☒ Return patents filed between Jan ▾ 1970 and Apr

Patents

Patents **1 - 20** on **fault location testing transient power supply current**. (0.05 seconds)

▸ **List view**

[Cover view](#)

[Integrated circuit **fault testing** implementing voltage **supply rail** pulsing ...](#)

US Pat. 5483170 - Filed Aug 24, 1993 - New Mexico State University Technology Transfer Corp.

▸ **Sort by relevance**

[Sort by date \(new first\)](#)

[Sort by date \(old first\)](#)

The pre-bias voltage will cause the **power supply** rails of the circuit to be tested to ... A simple **current** mirror detected the **transient current** (IDD) while

...

▸ **Any status**

[Issued patents](#)

[Applications](#)

[Fault location methods and apparatus using **current** pulse injection](#)

US Pat. 4377782 - Filed Jun 20, 1980 - Membrain Limited

via the bus 202, with its required **power** supplies and a sequence of test ... **transient** faults, since it ensures that the **fault** locating **current** pulse is ...

[Method for fabricating integrated circuit \(IC\) dies with multi-layered ...](#)

US Pat. 6423558 - Filed Feb 25, 2000 - Advantest Corporation

Accordingly, the quiescent **power supply current** test is very difficult to perform ... **fault** test, the 60 functional test, the exhaustive test, the **transient** ...

[Power line **fault** detector and analyzer](#)

US Pat. 6798211 - Filed Oct 29, 1998 - Remote Monitoring Systems, Inc.

6 to determine the **location** of the **fault**. The only difference is that the ... to detect a **transient** signal representing a **fault**; and a **power supply**, ...

[Multiprocessor for providing **fault** isolation test upon itself](#)

US Pat. 4181940 - Filed Feb 28, 1978 - Westinghouse Electric Corp.

With the resumption of normal **power supply** conditions, processors 10 and 12 ...

to isolate the **location** of a processor **fault** capable of causing said error; ...

[Method and apparatus for locating resistive faults in communication and ...](#)

US Pat. 5990686 - Filed Jun 18, 1996

1 is a chart showing the **transient** voltage conditions at the end of a long conductor; ... is closed to connect the **power supply** 16a to the conductor 10.

...

[System and method for locating faults in electric **power** cables](#)

US Pat. 5682100 - Filed Sep 6, 1995 - Electric Power Research Institute Inc.

4, the fault location system comprises a first and second counters 48 and

fault location testing transient power supply c

[Search Patents](#)

[Advanced Patent Search](#)

[Google Home](#) - [About Google](#) - [About Google Patents](#) - [Google Patents Help](#)

©2009 Google

Google

IDDT transient current

Search Pat

Filing date

☐ Return patents filed anytime

☒ Return patents filed between 1970 and

Patents

Patents **1 - 3** on **IDDT transient current**. (0.05 seconds)

▸ List view

[Cover view](#)

▸ Sort by relevance

[Sort by date \(new first\)](#)

[Sort by date \(old first\)](#)

▸ Any status

[Issued patents](#)

[Applications](#)

[Arrangement for **transient-current** testing of a digital electronic CMOS circuit](#)

US Pat. 6414511 - Filed Feb 7, 2000 - Koninklijke Philips Electronics N.V.
Generally, **transient-current** measurements or so-called **IDDT ...** "Defect Detection with **Transient Current** Testing and its Potential for Deep Sub-micron CMOS ...

[Method and apparatus for testing an integrated circuit with a pulsed ...](#)

US Pat. 6169408 - Filed Sep 30, 1996 - Motorola, Inc.
10, the IDD **transient current** spikes of Node A are filtered as taught herein.

However, the node C waveform of FIG. 10 illustrates the noise injected into ...

[Power converter](#)

US Pat. 4410936 - Filed Jan 18, 1982 - Oki Electric Industry Co., Ltd.
Thus, the decrease of the value $i_{...}$ increases the **current** in the diode 5, ... the present invention decreases the power loss in the switching **transient** in ...

Stay up to date on these results using [the patents RSS feed on IDDT transient current](#).

IDDT transient current

Search Patents

[Advanced Patent Search](#)

Google

DDT testing abnormal OR abnormality OR and

Search Pat

Filing date

☐ Return patents filed anytime

☒ Return patents filed between 1970 and

Patents

Patents 1 - 11 on **DDT testing abnormal OR abnormality OR anomaly**. (0.04 seconds)

› List view

[Cover view](#)

› Sort by relevance

[Sort by date \(new first\)](#)

[Sort by date \(old first\)](#)

› Any status

[Issued patents](#)

[Applications](#)

[CMOS integrated circuit failure diagnosis apparatus and diagnostic method](#)

US Pat. 5790565 - Filed Jan 13, 1997 - NEC Corporation

... a CMOS integrated all the patterns at which an Iddq **abnormality** is not ...

under test (**DDT**) 4 correspond- More specifically, from the results of a ...

[Integrated circuit early life failure detection by monitoring changes in ...](#)

US Pat. 6714032 - Filed Apr 25, 2000 - Agere System Inc.

40 present invention includes an apparatus for **testing** integrated Methods for

... measuring a current signature delta value of the integrated **ddt**, **testing**.
...

[Daphnia reproductive bioassay for testing toxicity of aqueous samples and ...](#)

US Pat. 6150126 - Filed Sep 16, 1998 - Wisconsin Alumni Research Foundation

... for example, **abnormal** swimming behavior, and **abnormal** motility. ...
chlorpyrifos, pentachlorophenol (PCP), and dichlorodiphenyl-trichloroethane (**DDT**)
); ...

[Environmental stress screening apparatus for electronic products](#)

US Pat. 4949031 - Filed Apr 5, 1988 - General Signal Corporation

Conventional The present invention relates to apparatus for **testing** ...
abnormal

or marginal parts hi manufac- environmental chambers and thus the ...

[CERTAIN THIADIAZOLES AS FUNGICIDES](#)

US Pat. 3764685 - Filed Sep 8, 1970

... tissue or the EXAMPLE 7 development of galls and other **abnormal** growths. ...

for example: **DDT**, methoxy- 40 trol of 100 percent for both types of fungus,
...

[HALO-L,Z,X-THIADIAZOLES](#)

US Pat. 3720684 - Filed Oct 13, 1970

The results of the test were as follows: compounds, for example: **DDT**,
methoxychlor, TDE, lindane, chlordane, ...

[Vascular endothelial growth factor C \(VEGF](#)

DDT testing abnormal OR abnormality OR ar

[Advanced Patent Search](#)

[Google Home](#) - [About Google](#) - [About Google Patents](#) - [Google Patents Help](#)

©2009 Google

Google

patents

Filing date

☐ Return patents filed anytime

☒ Return patents filed between 1970 and

Patents

Patents 1 - 17 on **fault location testing power supply "transient current"**. (0.05 seconds)

› List view

[Cover view](#)

[Integrated circuit **fault testing** implementing voltage **supply rail** pulsing ...](#)

US Pat. 5483170 - Filed Aug 24, 1993 - New Mexico State University Technology Transfer Corp.

› Sort by relevance

[Sort by date \(new first\)](#)

[Sort by date \(old first\)](#)

The pre-bias voltage will cause the **power supply** rails of the circuit to be tested to ... A simple current mirror detected the **transient current** (IDD) while

...

› Any status

[Issued patents](#)

[Applications](#)

[Fast recovery **power supply**](#)

US Pat. 4686462 - Filed Sep 26, 1985 - International Business Machines Corporation

Because capacitor 35 now recharges quickly the satu- **transient current** and quickly ... Thus, fast recovery **power supply**. the output 37 provides a measurable ...

[Method for fabricating integrated circuit \(IC\) dies with multi-layered ...](#)

US Pat. 6423558 - Filed Feb 25, 2000 - Advantest Corporation

The quiescent **power supply** current test is a procedure which assumes a ...

"

Defect Detection with **Transient Current Testing** 35 and its Potential for Deep

...

[Automatic controlled for an ice and snow melting system with ground **fault** ...](#)

US Pat. 5710408 - Filed Aug 15, 1996 - MSX, Inc.

The heater 14 **supply** leads are 35 Operating the switch 98 causes the test current to ... **transient current** flow that may occur upon application the two line ...

[Built-in test circuit for static CMOS circuits](#)

US Pat. 5097206 - Filed Oct 5, 1990 - Hewlett-Packard Company

power path between the **supply** voltage and the row The circuitry described ...

invention a voltage sensor that produces **fault** indicator signal includes, ...

[Rapid transit system **transient** voltage suppression apparatus](#)

US Pat. 4322772 - Filed Mar 21, 1980 - Westinghouse Electric Corp.

Therefor, for a given **fault** current condition and a given **power supply** ... of **transient current** within 10 milliseconds, as shown by curve 264 of FIG. 11.

...

fault location testing power supply "transient c Search Patents

Advanced Patent Search

[Google Home](#) - [About Google](#) - [About Google Patents](#) - [Google Patents Help](#)

©2009 Google